

- ★ Super Low Gate Charge
- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology



### Product Summary

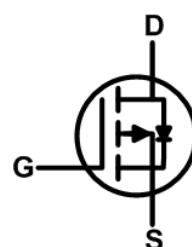
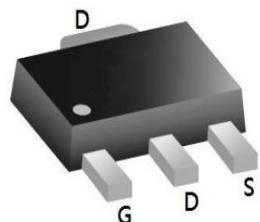
BVDSS	RDS(ON)	ID
-100V	185mΩ	-10A

### Description

The XXW10P10Q is the high cell density trenched N-ch MOSFETs, which provides excellent RDS(ON) and efficiency for most of the small power switching and load switch applications.

The XXW10P10Q meet the RoHS and Green Product requirement with full function reliability approved.

### SOT89-3L Pin Configuration



### Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	-100	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ -10V^1$	-10	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ -10V^1$	-4	A
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ -10V^1$	-2.5	A
$I_D @ T_A = 70^\circ C$	Continuous Drain Current, $V_{GS} @ -10V^1$	-2.0	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	-20	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	---	mJ
$I_{AS}$	Avalanche Current	---	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation <sup>4</sup>	2.4	W
$P_D @ T_A = 25^\circ C$	Total Power Dissipation <sup>4</sup>	1	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

### Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	---	69.4	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	---	8	°C/W

**P-Channel Electrical Characteristics ( $T_J=25^{\circ}\text{C}$ , unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}$ , $\text{I}_D=-250\mu\text{A}$	-100	---	---	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$\text{V}_{\text{GS}}=-10\text{V}$ , $\text{I}_D=-3\text{A}$	---	185	240	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=-4.5\text{V}$ , $\text{I}_D=-2\text{A}$	---	208	270	
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{GS}}=\text{V}_{\text{DS}}$ , $\text{I}_D=-250\mu\text{A}$	-1.2	-2	-2.3	V
$\text{I}_{\text{DSS}}$	Drain-Source Leakage Current	$\text{V}_{\text{DS}}=-100\text{V}$ , $\text{V}_{\text{GS}}=0\text{V}$ , $T_J=25^{\circ}\text{C}$	---	---	-1	$\text{uA}$
		$\text{V}_{\text{DS}}=-100\text{V}$ , $\text{V}_{\text{GS}}=0\text{V}$ , $T_J=85^{\circ}\text{C}$	---	---	-30	
$\text{I}_{\text{GSS}}$	Gate-Source Leakage Current	$\text{V}_{\text{GS}}=\pm 20\text{V}$ , $\text{V}_{\text{DS}}=0\text{V}$	---	---	$\pm 100$	nA
$\text{R}_g$	Gate Resistance	$\text{V}_{\text{DS}}=0\text{V}$ , $\text{V}_{\text{GS}}=0\text{V}$ , $f=1\text{MHz}$	---	---	---	$\Omega$
$\text{Q}_g$	Total Gate Charge (-10V)	$\text{V}_{\text{DS}}=-50\text{V}$ , $\text{V}_{\text{GS}}=-10\text{V}$ , $\text{I}_D=-2\text{A}$	---	29	---	$\text{nC}$
$\text{Q}_{\text{gs}}$	Gate-Source Charge		---	2.9	---	
$\text{Q}_{\text{gd}}$	Gate-Drain Charge		---	5.2	---	
$\text{T}_{\text{d(on)}}$	Turn-On Delay Time	$\text{V}_{\text{DD}}=-50\text{V}$ , $\text{V}_{\text{GS}}=-10\text{V}$ , $\text{R}_g=3.3\Omega$ , $\text{I}_D=-2\text{A}$	---	9.6	---	$\text{ns}$
$\text{T}_r$	Rise Time		---	17	---	
$\text{T}_{\text{d(off)}}$	Turn-Off Delay Time		---	60	---	
$\text{T}_f$	Fall Time		---	36	---	
$\text{C}_{\text{iss}}$	Input Capacitance	$\text{V}_{\text{DS}}=-50\text{V}$ , $\text{V}_{\text{GS}}=0\text{V}$ , $f=1\text{MHz}$	---	1290	---	$\text{pF}$
$\text{C}_{\text{oss}}$	Output Capacitance		---	34	---	
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance		---	28	---	

**Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$\text{I}_s$	Continuous Source Current <sup>1,5</sup>	$\text{V}_G=\text{V}_D=0\text{V}$ , Force Current	---	---	10.0	A
$\text{V}_{\text{SD}}$	Diode Forward Voltage <sup>2</sup>	$\text{V}_{\text{GS}}=0\text{V}$ , $\text{I}_s=-1\text{A}$ , $T_J=25^{\circ}\text{C}$	---	---	-1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq 300\text{us}$  , duty cycle  $\leq 2\%$
- 3.The power dissipation is limited by  $150^{\circ}\text{C}$  junction temperature
- 4.The data is theoretically the same as  $\text{I}_D$  and  $\text{I}_{\text{DM}}$  , in real applications , should be limited by total power dissipation.

## Typical Characteristics

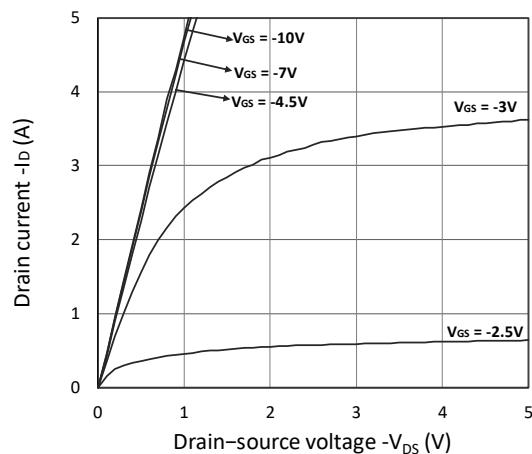


Figure 1. Output Characteristics

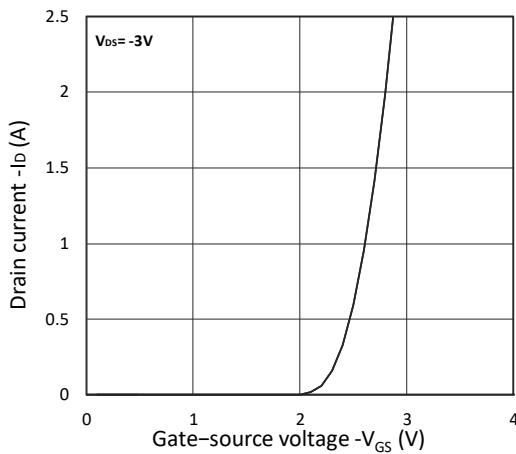


Figure 2. Transfer Characteristics

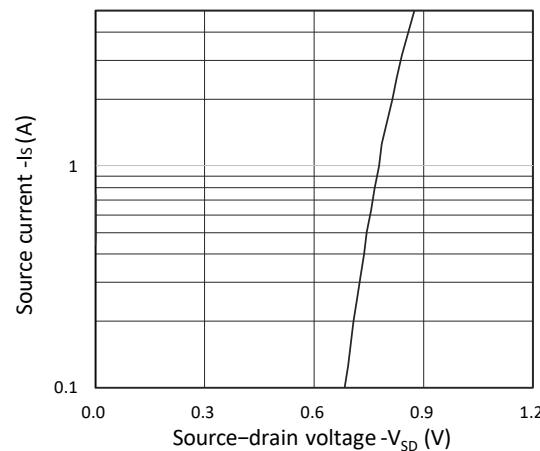


Figure 3. Forward Characteristics of Reverse

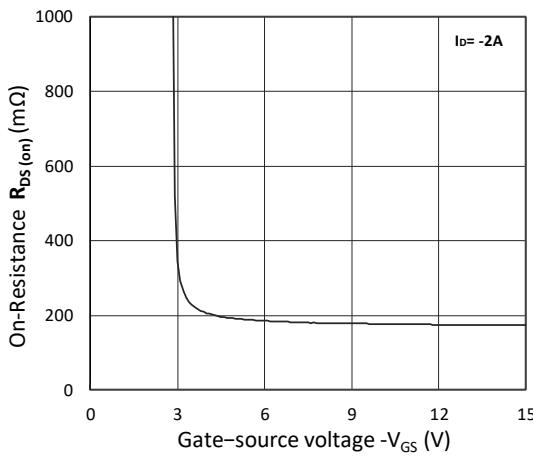


Figure 4.  $R_{DS(on)}$  vs.  $V_{GS}$

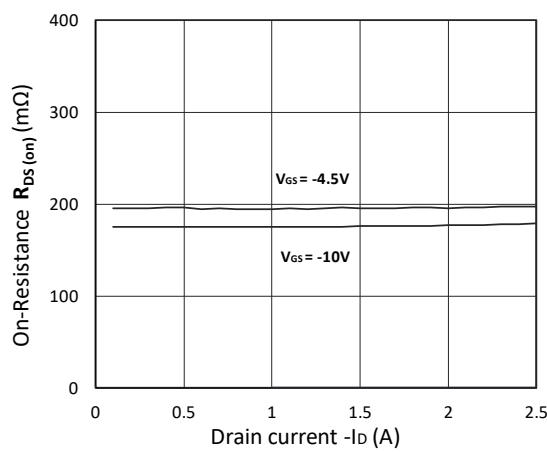


Figure 5.  $R_{DS(on)}$  vs.  $I_D$

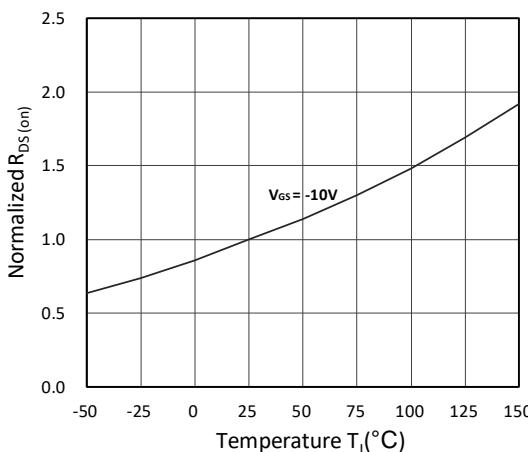


Figure 6. Normalized  $R_{DS(on)}$  vs. Temperature

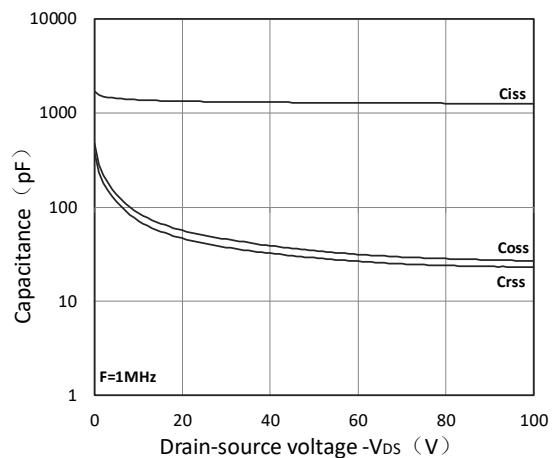


Figure 7. Capacitance Characteristics

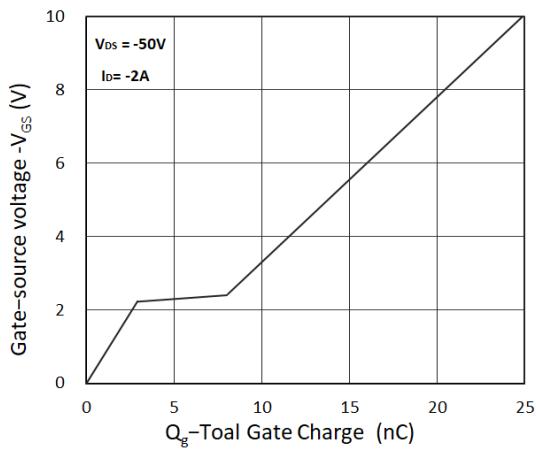
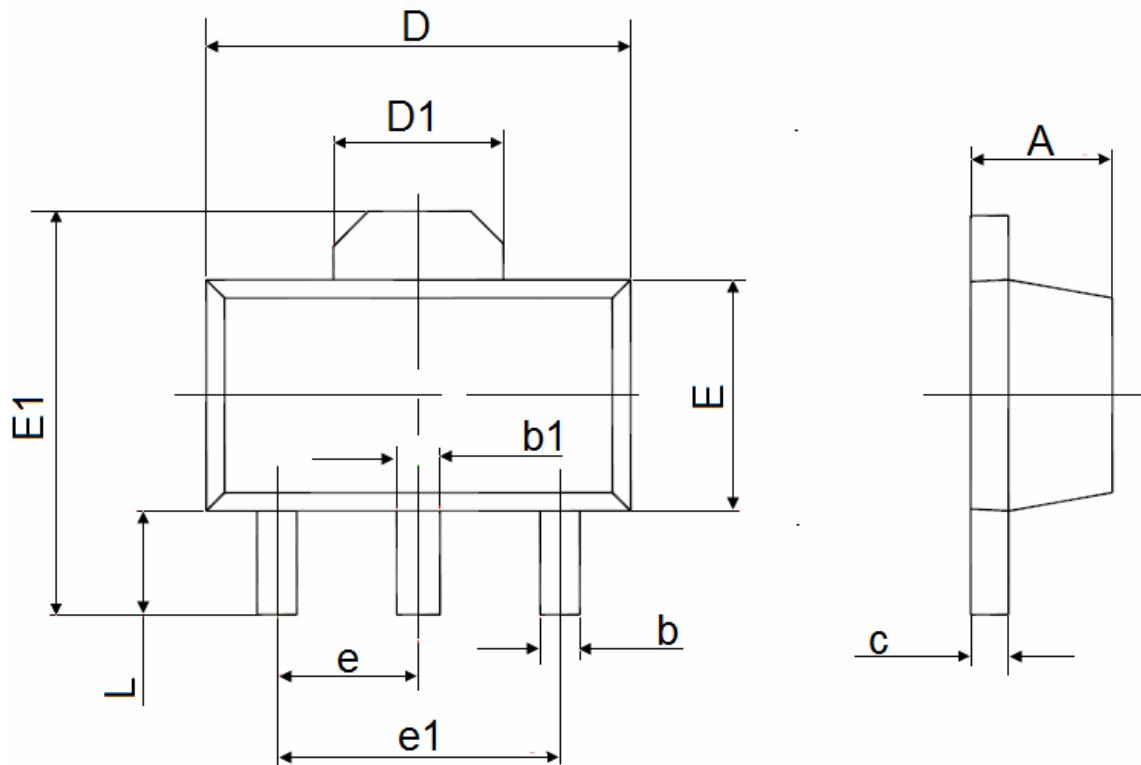


Figure 8. Gate Charge Characteristics

**SOT-89-3L Package Information**


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.400	1.600	0.055	0.063
b	0.320	0.520	0.013	0.020
b1	0.400	0.580	0.016	0.023
c	0.350	0.440	0.014	0.017
D	4.400	4.600	0.173	0.181
D1	1.550 REF.		0.061 REF.	
E	2.300	2.600	0.091	0.102
E1	3.940	4.250	0.155	0.167
e	1.500 TYP.		0.060 TYP.	
e1	3.000 TYP.		0.118 TYP.	
L	0.900	1.200	0.035	0.047